

# C3M0060065L

Silicon Carbide Power MOSFET

C3M™ MOSFET Technology

N-Channel Enhancement Mode

## Features

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery ( $Q_{rr}$ )
- Halogen free, RoHS compliant

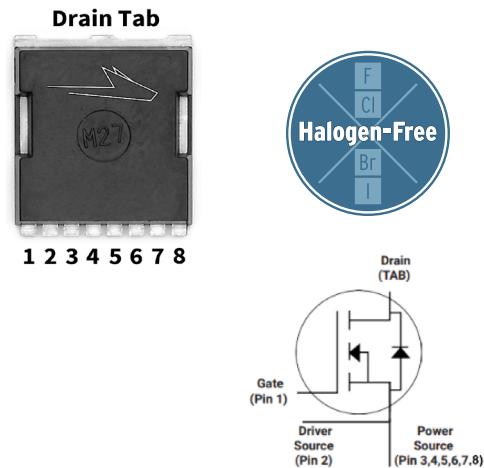
## Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

## Applications

- Datacenter Power Supplies
- Telecom Power Supplies
- Energy Storage Systems
- Solar (PV) inverters
- High Voltage DC/DC converters

## Package



Part Number	Package	Marking
C3M0060065L	TOLL	C3M0060065L

## Maximum Ratings ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit	Note	
$V_{DSmax}$	Drain - Source Voltage	650	V		
$V_{GSmax}$	Gate - Source Voltage	-8/+19	V	Note: 1	
$I_D$	Continuous Drain Current, $V_{GS} = 15\text{ V}$	$T_C = 25^\circ\text{C}$	39	A	Fig. 19 Note: 2
		$T_C = 100^\circ\text{C}$	25		
$I_{D(pulse)}$	Pulsed Drain Current, Pulse width $t_p$ limited by $T_{jmax}$	99	A	Fig. 22	
$P_D$	Power Dissipation, $T_c = 25^\circ\text{C}$ , $T_j = 175^\circ\text{C}$	131	W	Fig. 20 Note: 2	
$T_j$	Junction Temperature	-40 to +175	$^\circ\text{C}$		
$T_c, T_{stg}$	Case Temperature and Storage Temperature	-40 to +150	$^\circ\text{C}$		
$T_L$	Solder Temperature, 1.6mm (0.063") from case for 10s	260	$^\circ\text{C}$		

Note (1): Recommended turn off / turn on gate voltage  $V_{GS} = -4V...0V / +15V$

Note (2): Verified by design


**Electrical Characteristics** ( $T_C = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	650			V	$V_{GS} = 0\text{ V}, I_D = 100\ \mu\text{A}$	
$V_{GS(th)}$	Gate Threshold Voltage	1.8	2.8	3.6	V	$V_{DS} = V_{GS}, I_D = 3.64\ \text{mA}$	Fig. 11
			2.2		V	$V_{DS} = V_{GS}, I_D = 3.64\ \text{mA}, T_J = 175^\circ\text{C}$	
$I_{DSS}$	Zero Gate Voltage Drain Current		1	50	$\mu\text{A}$	$V_{DS} = 650\ \text{V}, V_{GS} = 0\ \text{V}$	
$I_{GSS}$	Gate-Source Leakage Current		10	250	nA	$V_{GS} = 15\ \text{V}, V_{DS} = 0\ \text{V}$	
$R_{DS(on)}$	Drain-Source On-State Resistance		60	79	m $\Omega$	$V_{GS} = 15\ \text{V}, I_D = 13.2\ \text{A}$	Fig. 4, 5, 6
			84			$V_{GS} = 15\ \text{V}, I_D = 13.2\ \text{A}, T_J = 175^\circ\text{C}$	
$g_{fs}$	Transconductance		9		S	$V_{DS} = 20\ \text{V}, I_{DS} = 13.2\ \text{A}$	Fig. 7
			9			$V_{DS} = 20\ \text{V}, I_{DS} = 13.2\ \text{A}, T_J = 175^\circ\text{C}$	
$C_{iss}$	Input Capacitance		1170		pF	$V_{GS} = 0\ \text{V}, V_{DS} = 400\ \text{V}$ $F = 1\ \text{MHz}$ $V_{AC} = 25\ \text{mV}$	Fig. 17, 18
$C_{oss}$	Output Capacitance		72				
$C_{rss}$	Reverse Transfer Capacitance		6				
$E_{oss}$	$C_{oss}$ Stored Energy		14		$\mu\text{J}$	$V_{DS} = 600\ \text{V}, F = 1\ \text{MHz}$	
$C_{o(er)}$	Effective Output Capacitance (Energy Related)		85		pF	$V_{GS} = 0\ \text{V}, V_{DS} = 0 \dots 400\ \text{V}$	Note: 3
$C_{o(tr)}$	Effective Output Capacitance (Time Related)		122		pF		
$E_{oN}$	Turn-On Switching Energy (Body Diode FWD)		28		$\mu\text{J}$	$V_{DS} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}, I_D = 13.2\ \text{A},$ $R_{G(ext)} = 2.5\ \Omega, L = 135\ \mu\text{H}, T_J = 25^\circ\text{C}$ FWD = Internal Body Diode	Fig. 23
$E_{oFF}$	Turn-Off Switching Energy (Body Diode FWD)		11				
$t_{d(on)}$	Turn-On Delay Time		6		ns	$V_{DD} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}$ $I_D = 13.2\ \text{A}, R_{G(ext)} = 2.5\ \Omega,$ Timing relative to $V_{DS}$ Inductive load	Fig. 26
$t_r$	Rise Time		8				
$t_{d(off)}$	Turn-Off Delay Time		14				
$t_f$	Fall Time		7				
$R_{G(int)}$	Internal Gate Resistance		4		$\Omega$	$f = 1\ \text{MHz}, V_{AC} = 25\ \text{mV}$	
$Q_{gs}$	Gate to Source Charge		16		nC	$V_{DS} = 400\ \text{V}, V_{GS} = -4\ \text{V}/15\ \text{V}$ $I_D = 13.2\ \text{A}$ Per IEC60747-8-4 pg 21	Fig. 12
$Q_{gd}$	Gate to Drain Charge		12				
$Q_g$	Total Gate Charge		46				

Note (3):  $C_{o(er)}$ , a lumped capacitance that gives same stored energy as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 400V  
 $C_{o(tr)}$ , a lumped capacitance that gives same charging time as  $C_{oss}$  while  $V_{ds}$  is rising from 0 to 400V


**Reverse Diode Characteristics** ( $T_c = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
$V_{SD}$	Diode Forward Voltage	4.6		V	$V_{GS} = -4\text{ V}, I_{SD} = 6.6\text{ A}, T_J = 25^\circ\text{C}$	Fig. 8, 9, 10
		4.1		V	$V_{GS} = -4\text{ V}, I_{SD} = 6.6\text{ A}, T_J = 175^\circ\text{C}$	
$I_S$	Continuous Diode Forward Current		22	A	$V_{GS} = -4\text{ V}, T_c = 25^\circ\text{C}$	
$I_{S, pulse}$	Diode pulse Current		99	A	$V_{GS} = -4\text{ V}$ , pulse width $t_p$ limited by $T_{Jmax}$	
$t_{rr}$	Reverse Recover time	9		ns	$V_{GS} = -4\text{ V}, I_{SD} = 13.2\text{ A}, V_R = 400\text{ V}$ $dif/dt = 5570\text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	142		nC		
$I_{rrm}$	Peak Reverse Recovery Current	33		A		
$t_{rr}$	Reverse Recover time	10		ns	$V_{GS} = -4\text{ V}, I_{SD} = 13.2\text{ A}, V_R = 400\text{ V}$ $dif/dt = 2160\text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$	
$Q_{rr}$	Reverse Recovery Charge	60		nC		
$I_{rrm}$	Peak Reverse Recovery Current	10		A		

**Thermal Characteristics**

Symbol	Parameter	Typ.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	0.89	$^\circ\text{C}/\text{W}$		Fig. 21



Typical Performance

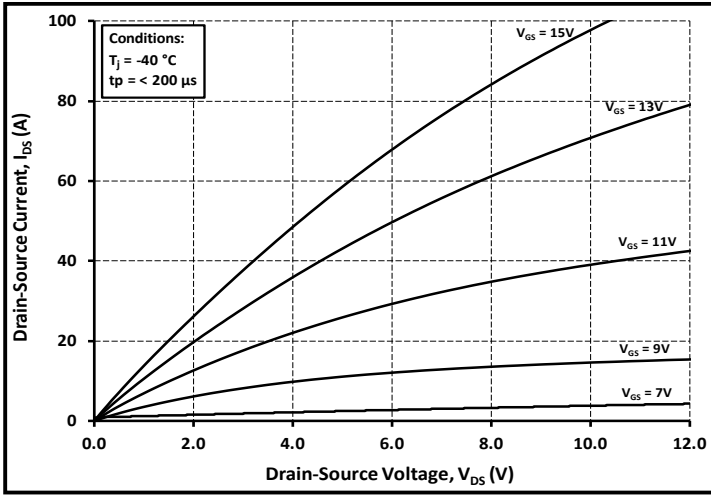


Figure 1. Output Characteristics  $T_J = -40\text{ }^\circ\text{C}$

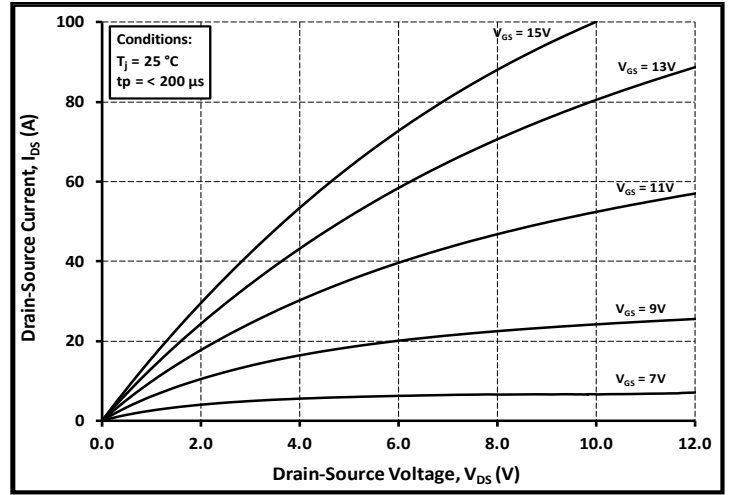


Figure 2. Output Characteristics  $T_J = 25\text{ }^\circ\text{C}$

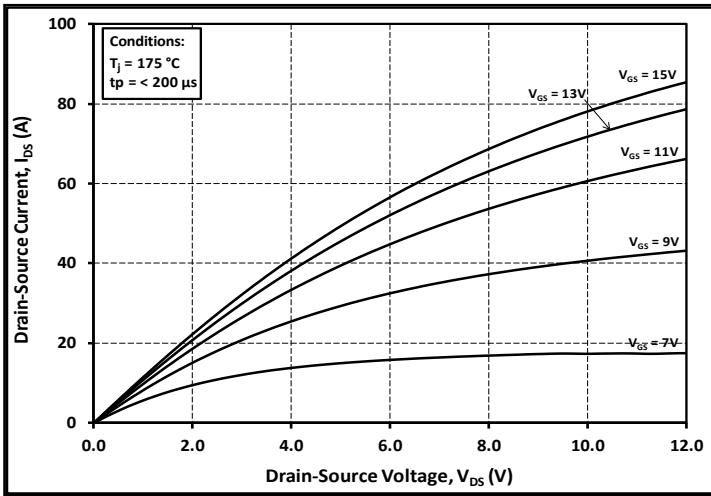


Figure 3. Output Characteristics  $T_J = 175\text{ }^\circ\text{C}$

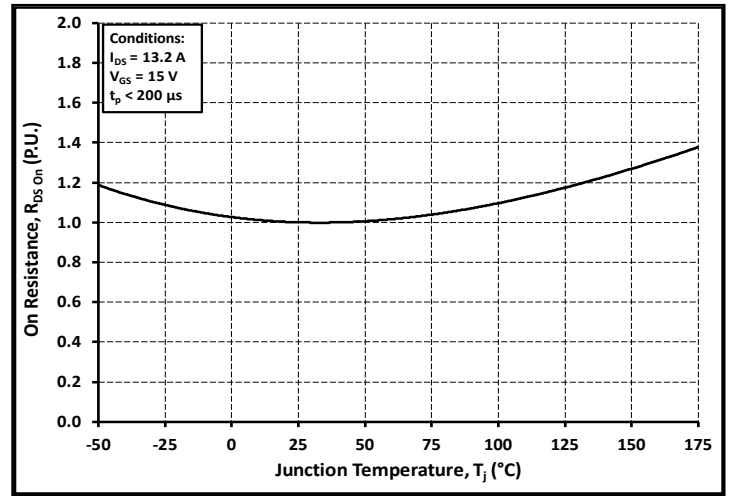


Figure 4. Normalized On-Resistance vs. Temperature

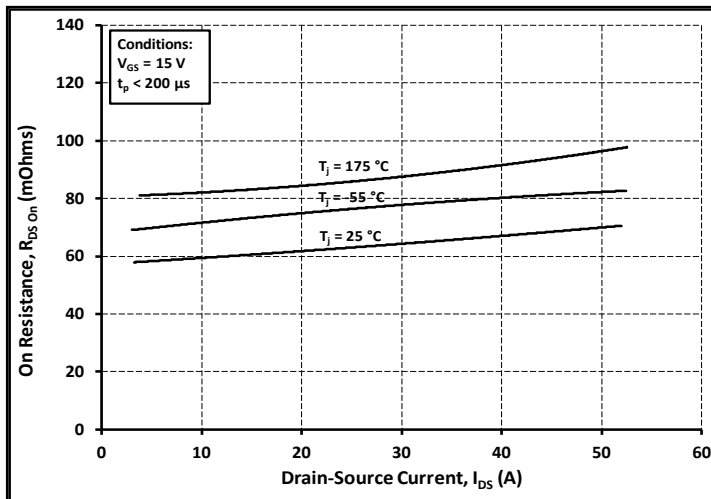


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

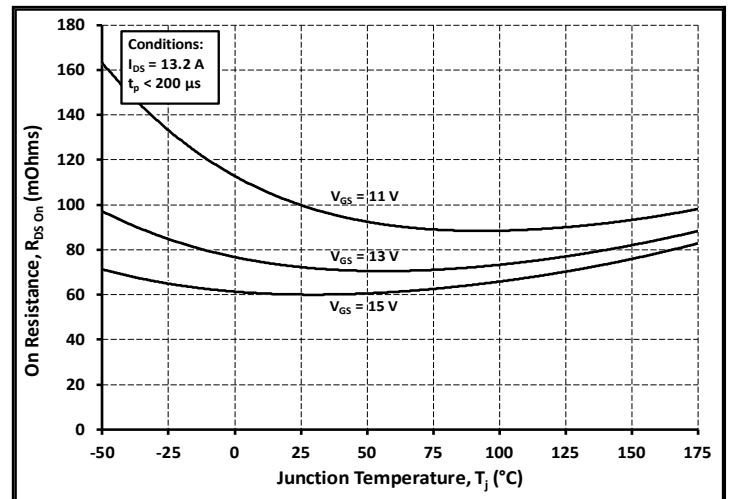


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage



Typical Performance

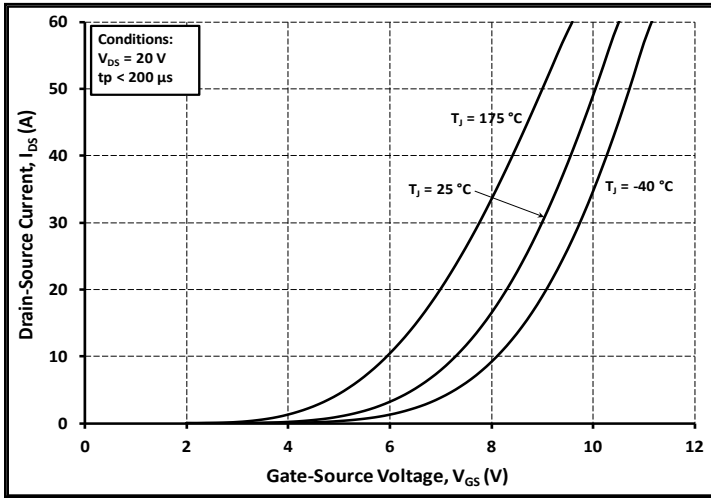


Figure 7. Transfer Characteristic for Various Junction Temperatures

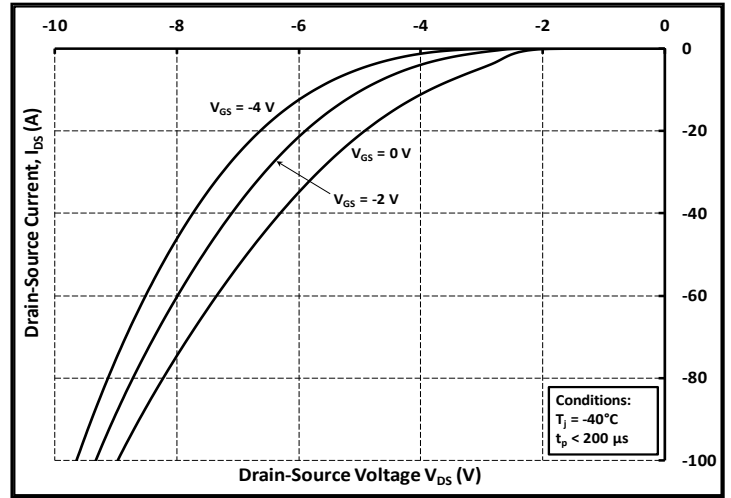


Figure 8. Body Diode Characteristic at -40 °C

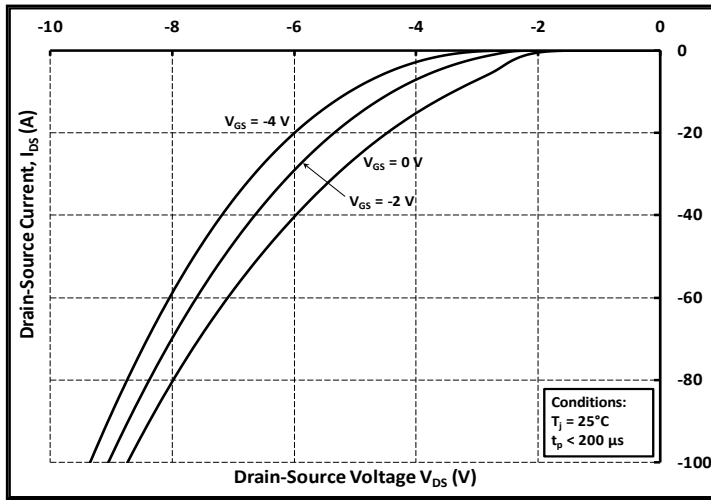


Figure 9. Body Diode Characteristic at 25 °C

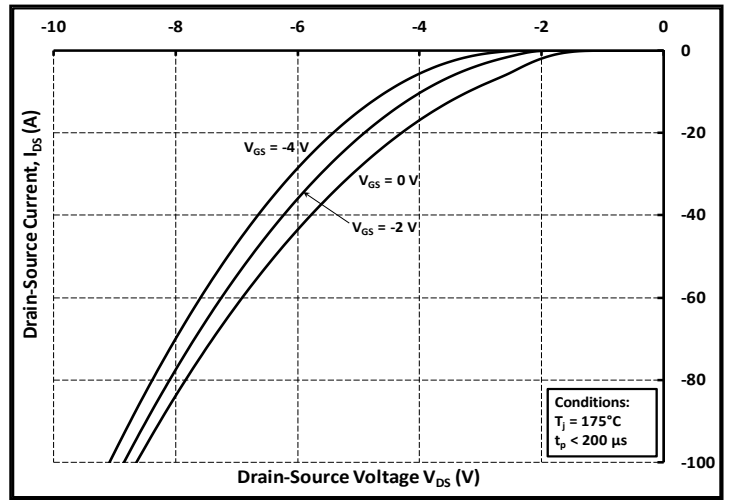


Figure 10. Body Diode Characteristic at 175 °C

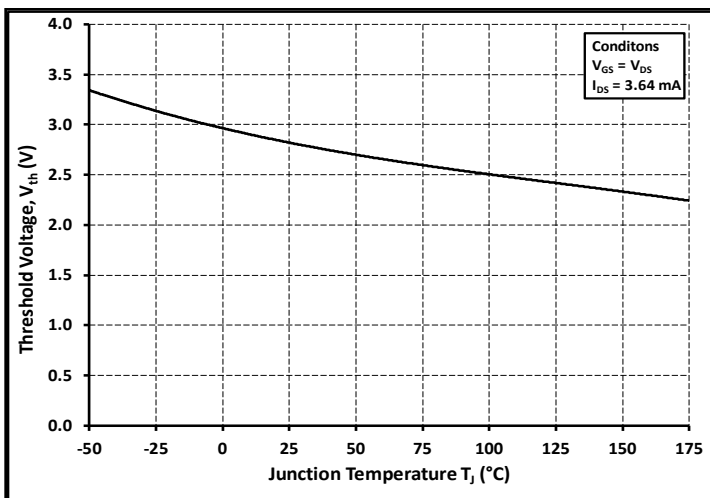


Figure 11. Threshold Voltage vs. Temperature

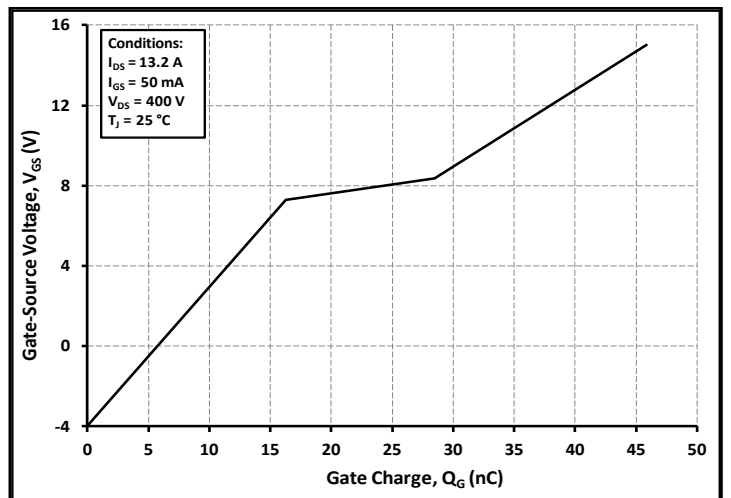


Figure 12. Gate Charge Characteristics



Typical Performance

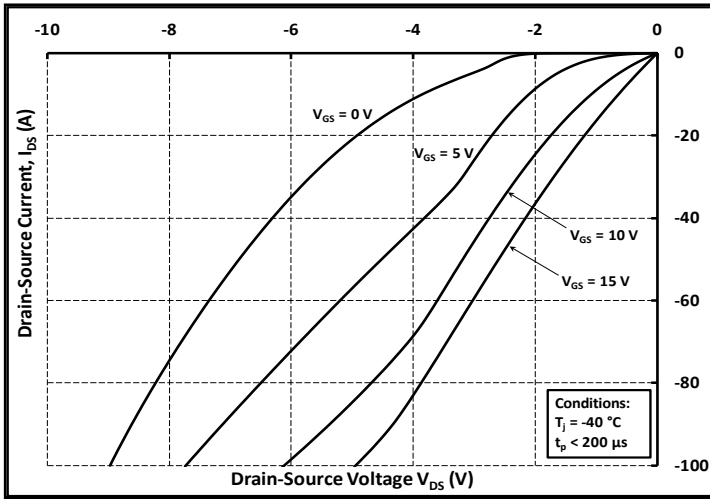


Figure 13. 3rd Quadrant Characteristic at -40 °C

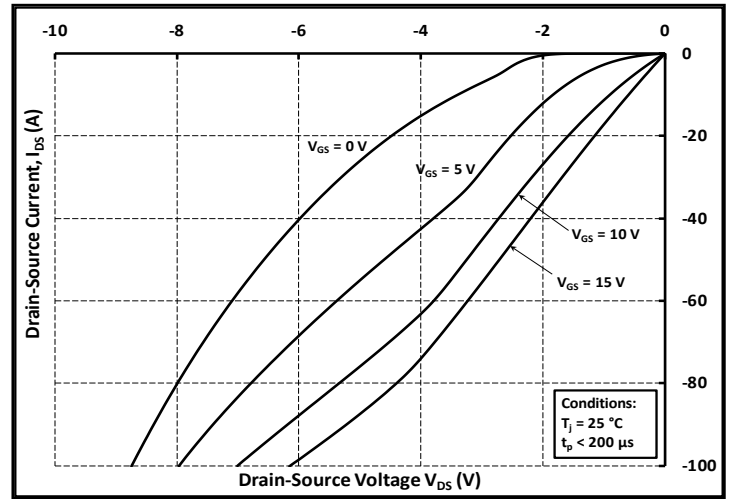


Figure 14. 3rd Quadrant Characteristic at 25 °C

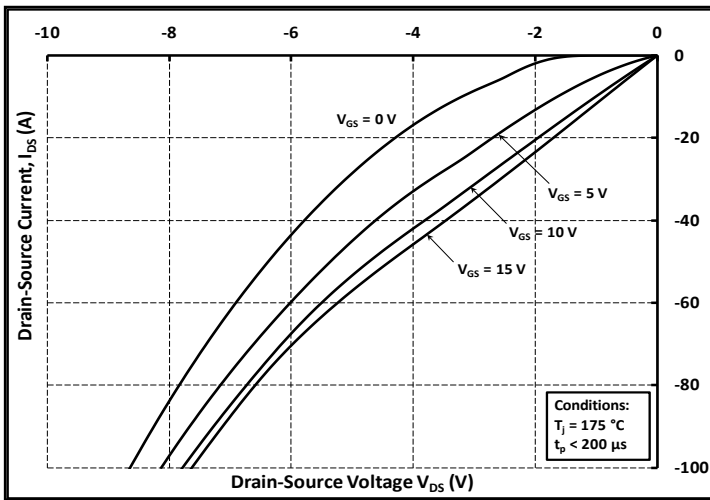


Figure 15. 3rd Quadrant Characteristic at 175 °C

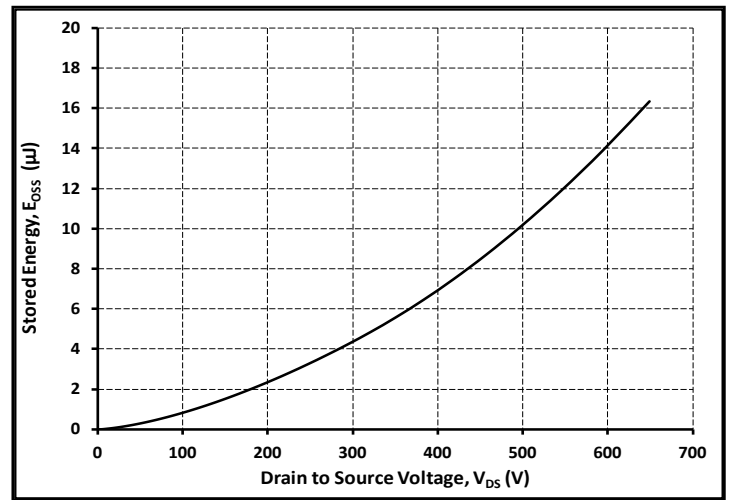


Figure 16. Output Capacitor Stored Energy

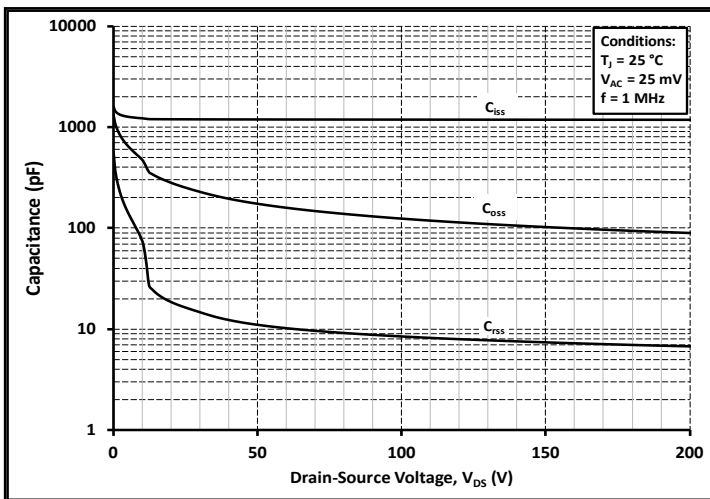


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

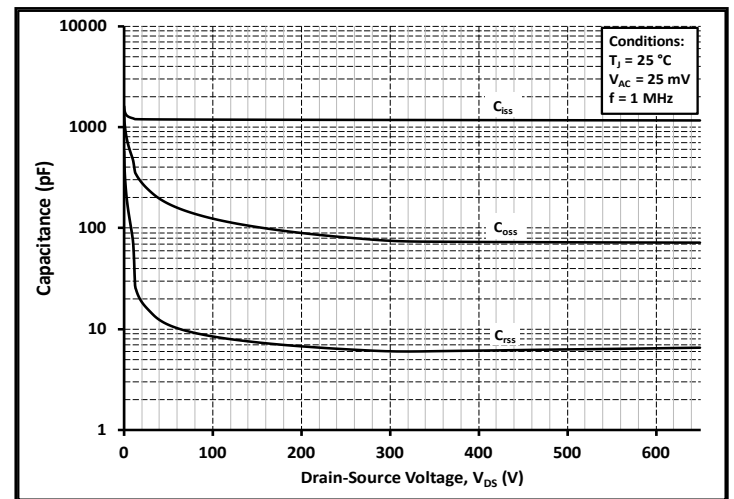


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 650V)



Typical Performance

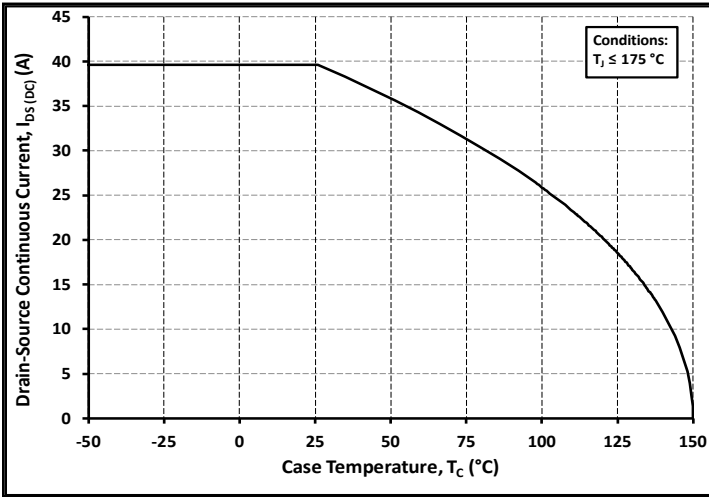


Figure 19. Continuous Drain Current Derating vs. Case Temperature

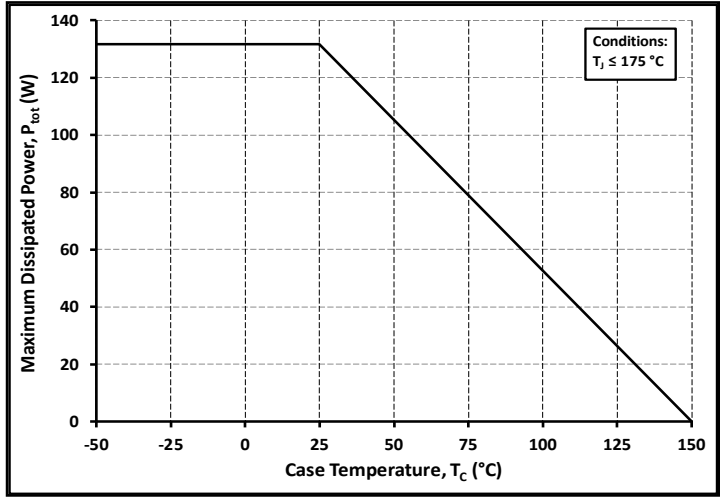


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

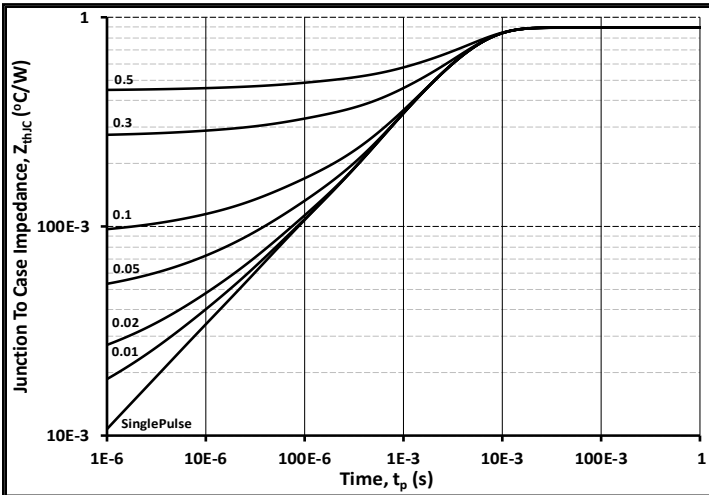


Figure 21. Transient Thermal Impedance (Junction - Case)

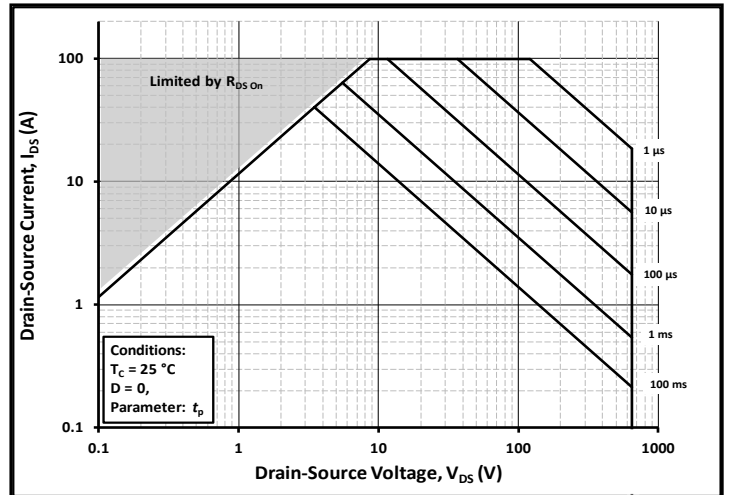


Figure 22. Safe Operating Area

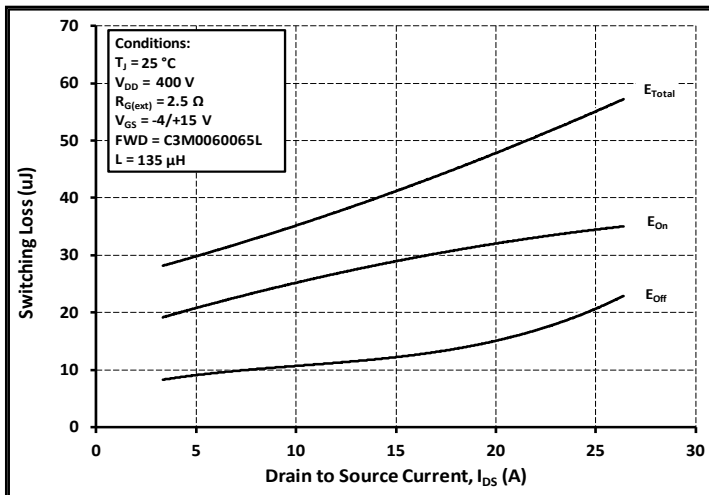


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ( $V_{DD} = 400V$ )

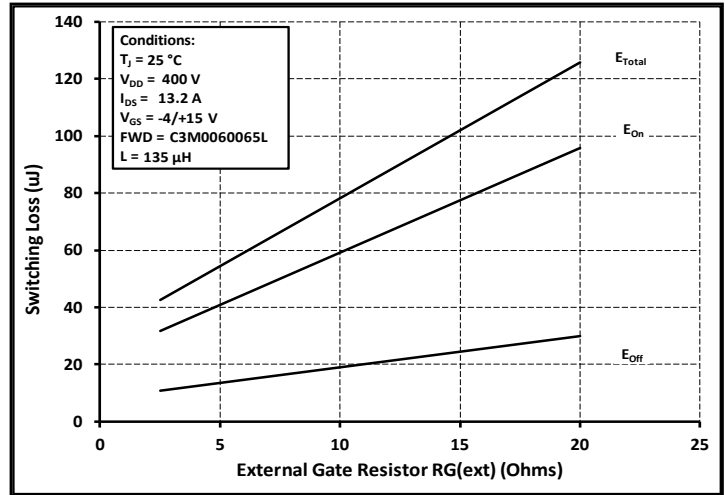


Figure 24. Clamped Inductive Switching Energy vs.  $R_{G(ext)}$



Typical Performance

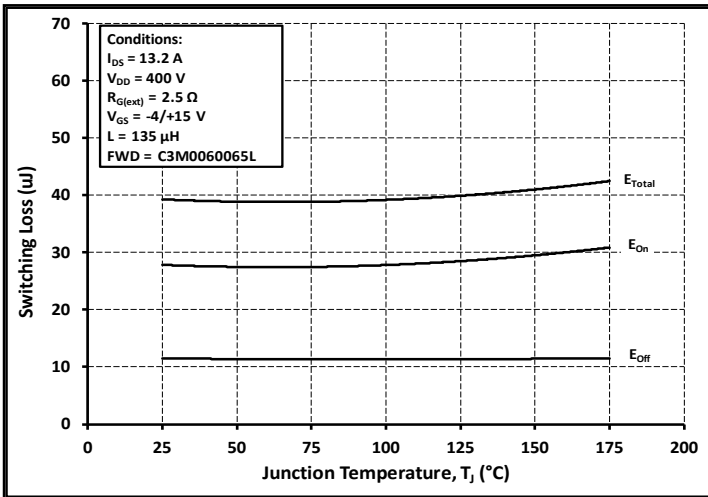


Figure 25. Clamped Inductive Switching Energy vs. Temperature

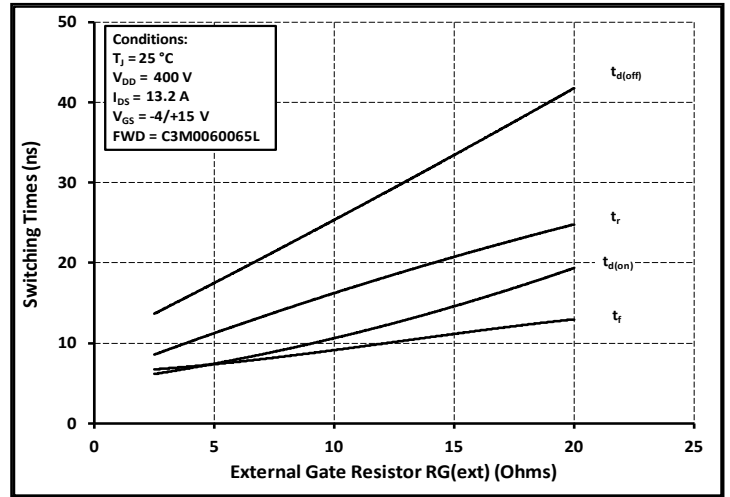


Figure 26. Switching Times vs.  $R_{G(ext)}$

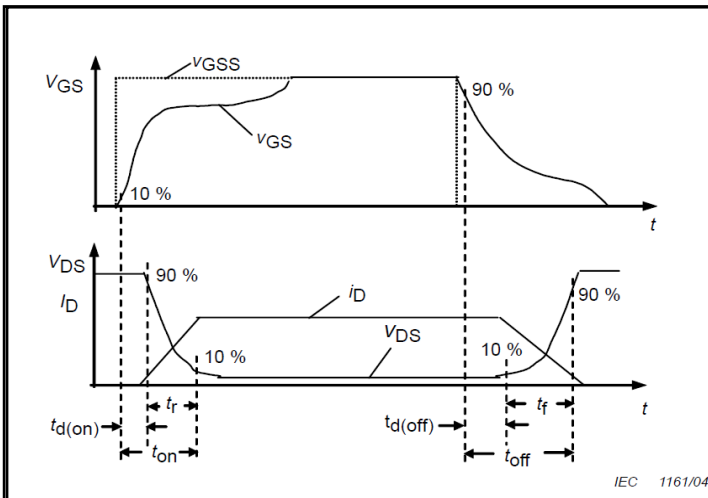


Figure 27. Switching Times Definition



## Test Circuit Schematic

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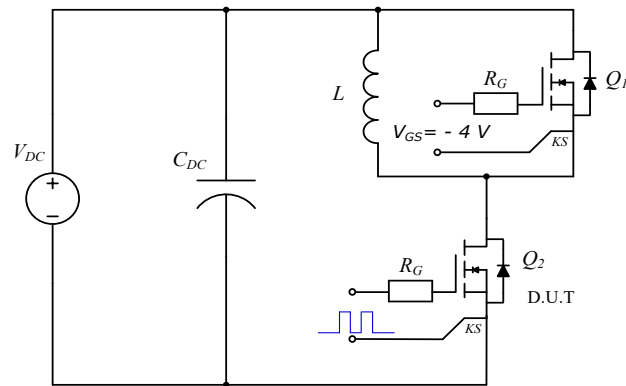
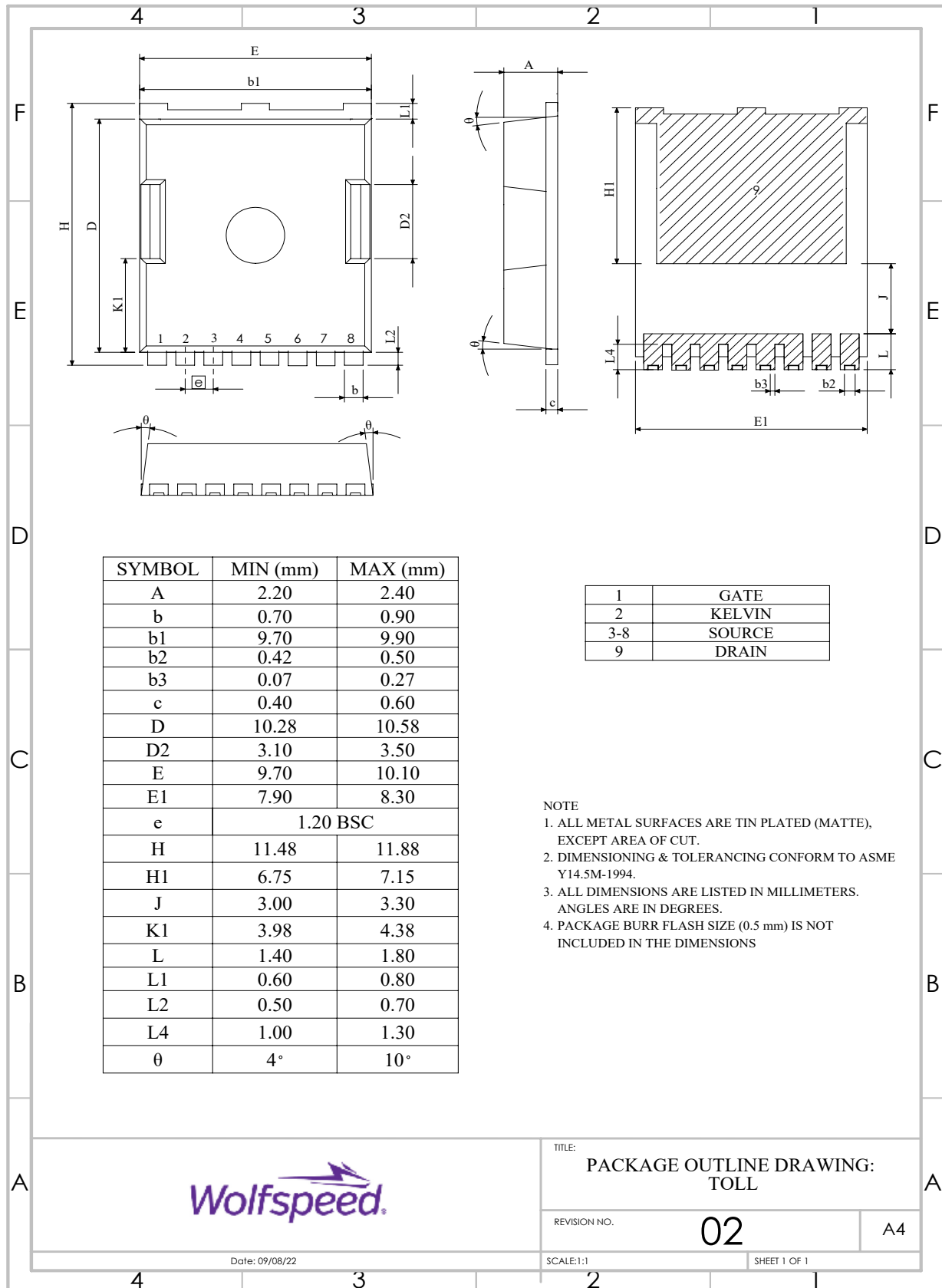


Figure 28. Clamped Inductive Switching Waveform Test Circuit

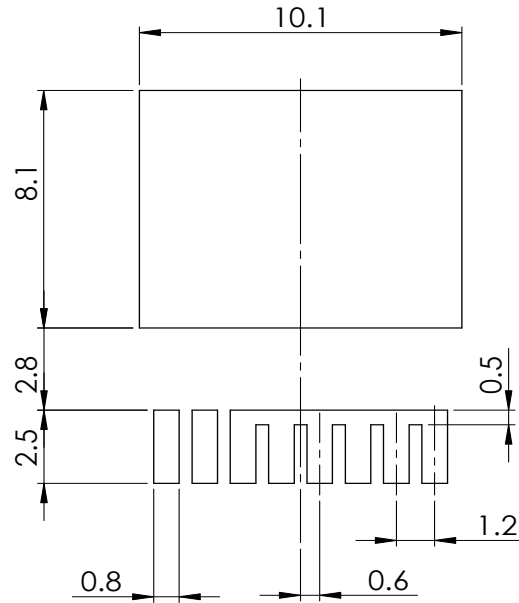
**Package Dimensions**





## Recommended Solder Pad Layout

(Note: All Dimensions are listed in Millimeters)





**Revision history**

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Document Version	Date of release	Description of changes
1.0	September-2022	Initial datasheet